

For more information, contact:

Debra Seifert  
Debra Seifert Communications  
(503) 626-7539  
[debra@debraseifert.com](mailto:debra@debraseifert.com)

David Oka  
Test Evolution  
(508) 377-5757 x7008  
[oka@testevolution.com](mailto:oka@testevolution.com)

**FOR IMMEDIATE RELEASE: November 5, 2010**

**Test Evolution Introduces First Standard Instruments for AXIe:  
Digital Pin and Device Power Modules**

**HOPKINTON, MA—November 5, 2010**—Test Evolution, the leading supplier of OEM test products based on the AXIe 3.1 open standard, today announced its first instrument modules as part of the *Evolution*® series of test systems focused on the semiconductor test market.

Test Evolution's new 48-Channel DD48 Digital Pin Module and the 12-channel DPS12 Digital Power Source module bring test capability in an open hardware and software platform for both device characterization and production test. Using common instruments and test programs lower the cost of test and speeds up time to volume production.

"The AXIe standard enables high performance instrumentation in an open standard modular solution. This will enable a renaissance in low cost, focused test solutions in semiconductor test applications," said Lev Alperovich, president, Test Evolution. "The DD48 and DPS12 will give customers the performance necessary to test today's digital and mixed-signal devices in an open platform, in both characterization and production environments, improving productivity, time to market, and ultimately profitability."

**About the DD48 Digital Pin Module**

The DD48 is an AXIe 3.1-compliant board with 48 400Mb/s (800Mb/s with channel multiplexing) channels in a single slot. The DD48 supports all the functionality of AXIe 3.1 including pattern-based triggering for inter-instrument control, 250MB/s PCI Express, in-system calibration support, and digitized waveform source, and capture. Up to 60 DD48 boards can be synchronized together, or subsets can be synchronized for multi-site testing. A robust pattern

sequencer is part of each DD48, allowing complex pattern flows. The DD48, with its rear transition connector provides for cable-less connections to semiconductor devices in both characterization and production testing.

### **About the DPS12 Digital Power Source**

The DPS12 is an AXIe 3.1-compliant board with 12 channels of 4-quadrant voltage and current force and measurement capability in a single slot. The DPS12 supports all the functionality of AXIe 3.1 including pattern-based triggering for inter-instrument control, 250MB/s PCI Express, and in-system calibration support. The DPS12 supports a voltage range from +22V down to -12V, and a current range from 1.2A (gang-able to 2.4A) down to 25uA, and includes 16-bit source and digitizer functionality with up to 32M samples, as well as various go/no-go testing features. The DPS12, with its rear transition connector provides for cable-less connections to semiconductor devices in both characterization and production testing.

"The AXIe 3.1 triggering capabilities allow for pattern based synchronization techniques, leading to better test repeatability and fast test times," said David Oka, vice president, engineering, Test Evolution. "The routing of test signals through the backplane and rear transition modules provides for cable-free test fixtures, a major boon for test repeatability. The DD48 and DPS12 provide true 'big iron' ATE features for the open market."

The DD48 and DPS12 are compatible with National Instrument's LabWindows® and TestStand®, and the IVI® software standard which are all widely used for device characterization, and easily coexists with PXI and LXI instruments and chassis. This capability allows for ATE instruments to be used for characterization, and later, the same instruments and test programs can be used in production, for both a cost and time savings for semiconductor device vendors.

### **Price and availability**

The DD48 and DPS12 are available immediately upon receipt of order. For more information and pricing on these or other products, contact David Oka at (508) 377-5757 or email [oka@testevolution.com](mailto:oka@testevolution.com).

### **About AXIe**

AXIe is a standard based on AdvancedTCA® with extensions for instrumentation and test. The mission of the AXIe Consortium is to provide an open standard that creates a robust ecosystem

of components, products and systems for general-purpose instrumentation and semiconductor test. AXIe leverages existing standards from PXI, LXI, and IVI. AXIe promises high scalability and performance that will address a range of platforms including bench top measurements, rack-and-stack modular, and ATE systems. [www.axiestandard.org](http://www.axiestandard.org)

### **About Test Evolution**

With expertise in digital, mixed-signal, and RF instrumentation, Test Evolution is offering a unique way of developing OEM ATE technology, providing the engineering expertise to develop test instruments, sub-systems and systems in an open standard format for ATE providers, system integrators, semiconductor test houses, and silicon vendors. Test Evolution is a founding member of the AXIe Consortium. Information about Test Evolution is available on the Web at [www.testevolution.com](http://www.testevolution.com).

---

CVI, LabVIEW, National Instruments & NI TestStand are trademarks of National Instruments. IVI is a registered trademark of the IVI Foundation.